ACFL-5212T

Automotive R²Coupler[™] Wide Operating Temperature 20kBd Digital Optocoupler Configurable as Low Power, Low Leakage Phototransistor

Data Sheet

Description

The ACFL-5212T is an automotive grade dual channel, bidirectional, high CMR, 20kBd digital optocoupler, configurable as a low power, low leakage phototransistor, specifically for use in automotive applications. The stretched SO-12 package outline is designed to be compatible with standard surface mount processes and occupies the same land area as the single channel equivalent, ACPL-K49T, in stretched SO8 package.

This digital optocoupler uses an insulating layer between the light emitting diode and an integrated photo detector to provide electrical insulation between input and output. Separate connections for the photodiode bias and output transistor collector increase the speed up to a hundred times over that of a conventional photo-transistor coupler by reducing the base-collector capacitance.

Each channel is also galvanically isolated from each other with no cross-talk.

Avago R2Coupler provides reinforced insulation and reliability that delivers safe signal isolation critical in automotive and high temperature industrial applications.

Features

- Qualified to AEC Q100 Grade 1 Guidelines
- Wide Temperature Range: -40°C to +125°C
- Low LED Drive Current: 4mA (typ)
- Low Power, Low Leakage Phototransistor in a "4-pin Configuration" ($I_{(CEO)}$ < 5µA)
- 30 kV/ μ s High Common-Mode Rejection at V_{CM} = 1500 V (typ)
- Low Propagation Delay: 20µs (max)
- Compact, Auto-Insertable Stretched SO12 Packages
- Worldwide Safety Approval:
	- UL 1577 recognized, 5kV_{RMS}/1 min.
	- CSA Component Acceptance Notice#5A
	- IEC/EN/DIN EN 60747-5-5

Applications

- Automotive Low Speed Digital Signal Isolation Interface
- Inverter Fault Feedback Signal Isolation
- Switching Power Supplies Feedback Circuit

Functional Diagram

Note: The connection of a 1 μF bypass capacitor between pins 1 and 3 and pins 8 and 10 is recommended.

Note: Pins 1 and 2 and pins 9 and 10 are externally shorted for 4-pin configuration. Do not connect bypass capacitors in this configuration.

CAUTION: It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD. The components featured in this datasheet are not to be used in military or aerospace applications or environments.

Pin Description

Ordering Information

To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry.

Example 1:

ACFL-5212T-560E to order product of SSO-12 Surface Mount package in Tape and Reel packaging with IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

Option datasheets are available. Contact your Avago sales representative or authorized distributor for information.

Package Outline Drawing

12-Lead Surface Mount

Dimensions in inches (millimeters) Lead coplanarity = 0.004 inches $(0.1$ mm)

Recommended Pb-Free IR Profile

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision).

Note: Non-halide flux should be used

Regulatory Information

The ACFL-5212T is approved by the following organizations:

Insulation and Safety Related Specifications

IEC / EN / DIN EN 60747-5-5 Insulation Related Characteristic (Option 060E and 560E)

Absolute Maximum Ratings

Recommended Operating Conditions

Electrical Specifications (DC) for 5-Pin Configuration

Over recommended operating conditions, unless otherwise specified. All typical specifications are at $T_A=25^{\circ}$ C, V_{CC}= 5V.

Switching Specifications (AC) for 5-Pin Configuration

Over recommended operating conditions, unless otherwise specified. All typical specifications are at $T_A=25^{\circ}$ C, V_{CC}= 5V.

Electrical Specifications (DC) for 4-Pin Configuration

Over recommended operating conditions, unless otherwise specified. All typical specifications are at $T_A=25^{\circ}$ C, V_{CC}= 5V.

Switching Specifications (AC) for 4-Pin Configuration

Over recommended operating conditions, unless otherwise specified. All typical specifications are at $T_A=25^{\circ}$ C, V_{CC}= 5V.

Package Characteristics

All Typical at $T_A = 25^{\circ}$ C.

The Input-Output Momentary Withstand Voltage is a dielectric voltage rating that should not be interpreted as an input-output continuous voltage rating.

Notes:

1. Current Transfer Ratio in percent is defined as the ratio of output collector current, I_O, to the forward LED input current, IF, times 100.

2. Use of 1μ F bypass capacitors connected between pins 1 and 3 and pins 8 and 10 for 5-pin configuration.

3. Common transient immunity in a Logic High level is the maximum tolerable (positive) dV_{CM}/dt on the rising edge of the common mode pulse, V_{CM}, to assure that the ouput will remain in a Logic High state (i.e., $V_O > 2.0V$). Common mode transient immunity in a Logic Low level is the maximum tolerable (negative) dV_{CM}/dt on the falling edge of the common mode pulse signal, V_{CM} to assure that the output will remain in a Logic Low state (i.e., $V_O < 0.8V$).

4. Device considered a two terminal device: pins 1 to 6 shorted together, and pins 7 to 12 shorted together.

5. In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage > 6000VRMS for 1 second.

Typical Performance Plots

Figure 1. Current Transfer Ratio vs. Input Current Figure 2. Normalized Current Transfer Ratio vs. Temperature

Figure 5. Typical Low Level Output Current vs Output Voltage (4-Pin Configuration)

Figure 6. Typical Input Current vs Forward Voltage

Figure 7. Typical High Level Output Current vs Temperature Figure 8. Typical Off-State Current vs Temperature (4-Pin Configuration)

Test Circuits

Figure 9. Switching Test Circuit (5-pin Configuration)

Figure 10. Switching Test Circuit (4-pin Configuration)

SWITCH AT B: IF = 10mA

5V

 $-v_{0L}$

Figure 11. Test Circuit for Transient Immunity and Typical Waveforms (5-Pin Configuration)

Figure 12. Test Circuit for Transient Immunity and Typical Waveforms (4-Pin Configuration)

Thermal Resistance Measurement

The diagram of ACFL-5212T for measurement is shown in Figure 13. This is a multi-chip package with four heat sources, the effect of heating of one die due to the adjacent dice are considered by applying the theory of linear superposition. Here, one die is heated first and the temperatures of all the dice are recorded after thermal equilibrium is reached. Then, the 2nd die is heated and all the dice temperatures are recorded and so on until the 4th die is heated. With the known ambient temperature, the die junction temperature and power dissipation, the thermal resistance can be calculated. The thermal resistance calculation can be cast in matrix form. This yields a 4 by 4 matrix for our case of two heat sources.

R11: Thermal Resistance of Die1 due to heating of Die1 (˚C/W) R12: Thermal Resistance of Die1 due to heating of Die2 (˚C/W) R13: Thermal Resistance of Die1 due to heating of Die3 (˚C/W) R14: Thermal Resistance of Die1 due to heating of Die4 (˚C/W)

R21: Thermal Resistance of Die2 due to heating of Die1 (˚C/W) R22: Thermal Resistance of Die2 due to heating of Die2 (˚C/W) R23: Thermal Resistance of Die2 due to heating of Die3 (˚C/W) R24: Thermal Resistance of Die2 due to heating of Die4 (˚C/W)

R31: Thermal Resistance of Die3 due to heating of Die1 (˚C/W) R32: Thermal Resistance of Die3 due to heating of Die2 (˚C/W) R33: Thermal Resistance of Die3 due to heating of Die3 (˚C/W) R34: Thermal Resistance of Die3 due to heating of Die4 (˚C/W)

R41: Thermal Resistance of Die4 due to heating of Die1 (˚C/W) R42: Thermal Resistance of Die4 due to heating of Die2 (˚C/W) R43: Thermal Resistance of Die4 due to heating of Die3 (˚C/W) R44: Thermal Resistance of Die4 due to heating of Die4 (˚C/W)

P1: Power dissipation of Die1 (W) P2: Power dissipation of Die2 (W) P3: Power dissipation of Die3 (W) P4: Power dissipation of Die4 (W)

T₁: Junction temperature of Die1 due to heat from all dice (\degree C) T₂: Junction temperature of Die2 due to heat from all dice ($^{\circ}$ C) T₃: Junction temperature of Die3 due to heat from all dice $(^{\circ}C)$ T4: Junction temperature of Die4 due to heat from all dice (°C)

Ta: Ambient temperature.

 ΔT_1 : Temperature difference between Die1 junction and ambient (°C) ∆T2: Temperature deference between Die2 junction and ambient (°C) ∆T3: Temperature difference between Die3 junction and ambient (°C) ∆T4: Temperature deference between Die4 junction and ambient (°C)

Figure 13. Diagram of ACFL-5212T for measurement

Measurement data on a low K (conductivity) board:

 $R_{11} = 181 °C/W$ $R_{21} = 103 °C/W$ $R_{31} = 82 °C/W$ $R_{41} = 110 °C/W$ $R_{12} = 91 °C/W$ $R_{22} = 232 °C/W$ $R_{32} = 97 °C/W$ $R_{42} = 86 °C/W$ $R_{13} = 85 °C/W$ $R_{23} = 109 °C/W$ $R_{33} = 180 °C/W$ $R_{43} = 101 °C/W$ $R_{14} = 112 °C/W$ $R_{24} = 91 °C/W$ $R_{34} = 91 °C/W$ $R_{44} = 277 °C/W$

Measurement data on a high K (conductivity) board:

 $R_{11} = 117 °C/W$ $R_{21} = 37 °C/W$ $R_{31} = 35 °C/W$ $R_{41} = 47 °C/W$ $R_{12} = 42 °C/W$ $R_{22} = 161 °C/W$ $R_{32} = 53^{\circ}$ C/W $R_{42} = 30 °C/W$ $R_{13} = 32 °C/W$ $R_{23} = 39 °C/W$ $R_{33} = 114 °C/W$ $R_{43} = 29 °C/W$ $R_{14} = 60 °C/W$ $R_{24} = 33 °C/W$ $R_{34} = 34 °C/W$ $R_{44} = 189 °C/W$